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## Guide for Measurement of Ionizing Dose-Rate Survivability and Burnout of Semiconductor Devices<sup>1</sup>

This standard is issued under the fixed designation F1893; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon ( $\epsilon$ ) indicates an editorial change since the last revision or reapproval.

### 1. Scope

1.1 This guide defines the detailed requirements for testing semiconductor devices for short-pulse high dose-rate ionization-induced survivability and burnout failure. The test facility shall be capable of providing the necessary dose rates to perform the measurements. Typically, large flash X-ray (FXR) machines operated in the photon mode, or FXR e-beam facilities are utilized because of their high dose-rate capabilities. Electron Linear Accelerators (LINACs) may be used if the dose rate is sufficient. Two modes of test are described: (1) A survivability test, and (2) A burnout failure level test.

1.2 The values stated in International System of Units (SI) are to be regarded as standard. No other units of measurement are included in this standard.

1.3 *This international standard was developed in accordance with internationally recognized principles on standardization established in the Decision on Principles for the Development of International Standards, Guides and Recommendations issued by the World Trade Organization Technical Barriers to Trade (TBT) Committee.*

### 2. Referenced Documents

2.1 *ASTM Standards:*<sup>2</sup>

**E170 Terminology Relating to Radiation Measurements and Dosimetry**

**E668 Practice for Application of Thermoluminescence-Dosimetry (TLD) Systems for Determining Absorbed Dose in Radiation-Hardness Testing of Electronic Devices**

**E1894 Guide for Selecting Dosimetry Systems for Application in Pulsed X-Ray Sources**

**F526 Test Method for Using Calorimeters for Total Dose Measurements in Pulsed Linear Accelerator or Flash X-ray Machines**

2.2 *ISO/ASTM Standard:*<sup>2</sup>

**51275 Practice for Use of a Radiochromic Film Dosimetry System – 18**

### 3. Terminology

3.1 *Definitions:*

3.1.1 *burnout failure level test*—a test performed to determine the maximum dose-rate level the device survives and the minimum dose-rate level where the device experiences burnout.

3.1.1.1 *Discussion*—

In such a test, semiconductor devices are exposed to a series of irradiations of increasing dose-rate levels. The maximum dose rate at which the device survives is determined for worst-case bias conditions. The burnout failure level test is always a destructive test.

3.1.2 *dose rate*—the amount of energy absorbed per unit mass of a material per unit time during exposure to the radiation field (typically, expressed in units of Gy(material)/s). For pulsed radiation sources, dose rate typically refers to the peak dose rate during the pulse.

3.1.3 *dose rate induced latchup*—regenerative device action in which a parasitic region (for example, a four (4) layer p-n-p-n or n-p-n-p path) is turned on by the photocurrent generated by a pulse of ionizing radiation, and remains on for an indefinite period

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<sup>2</sup> For referenced ASTM standards, visit the ASTM website, www.astm.org, or contact ASTM Customer Service at service@astm.org. For *Annual Book of ASTM Standards* volume information, refer to the standard's Document Summary page on the ASTM website.

of time after the photocurrent subsides. The device will remain latched as long as the power supply delivers voltage greater than the holding voltage and current greater than the holding current. Latchup disrupts normal circuit operation in some portion of the circuit, and may also cause catastrophic failure due to local heating of semiconductor regions, metallization or bond wires.

3.1.4 *failure condition*—a device is considered to have undergone burnout failure if the device experiences one of the following conditions.

(1) *functional failure*—a device failure where the device under test, (DUT) fails functional tests following exposure.

(2) *parametric failure*—a device failure where the device under test, (DUT) fails parametric measurements after exposure.

#### 3.1.4.1 *Discussion*—

Functional or parametric failures may be caused by total ionizing dose mechanisms. See interferences for additional discussion.

3.1.5 *high dose-rate burnout*—permanent damage to a semiconductor device caused by abnormally large currents flowing in junctions and resulting in a discontinuity in the normal current flow in the device.

#### 3.1.5.1 *Discussion*—

This effect strongly depends on the mode of operation and bias conditions. Temperature may also be a factor in damage to the device should latchup occur prior to failure. Latchup is known to be temperature dependent.

3.1.6 *ionizing dose rate response*—the transient changes which occur in the operating parameters or in the output signal of an operating device when exposed to an ionizing radiation pulse. See Terminology E170 for a definition of ionization. Within this standard, the scope of the dose rate response is restricted to consideration of linear microcircuits.

3.1.7 *ionizing radiation effects*—the changes in the electrical parameters of a microelectronic device resulting from radiation-induced trapped charge. These are also sometimes referred to as “total dose effects.”

3.1.8 *latchup window*—a latchup window is the phenomenon in which a device exhibits latchup in a specific range of dose rates. Above and below this range, the device does not latchup. A device may exhibit more than one latchup window. This phenomenon has been observed for some complementary metal-oxide semiconductor (CMOS) logic devices, oxide sidewall logic devices and large scale integration (LSI) memories and may occur in other devices.

3.1.9 *survivability test*—A “pass/fail” test performed to determine the status of the device after being exposed to a predetermined dose-rate level. The survivability test is usually considered a destructive test.

## 4. Summary of Guide

4.1 Semiconductor devices are tested for burnout during and after exposure to an ionizing high dose-rate radiation pulse. The measurement is deemed as a survivability test when the test criteria is a pass/fail measurement at a predetermined dose-rate level, or deemed as a burnout failure level test when the maximum passing dose-rate level and the minimum failing dose rate level for burnout is determined experimentally.

4.2 The following quantities are unspecified in this guide and must be agreed upon between the parties to the test:

4.2.1 The maximum ionizing dose (total dose to which the devices will be subjected during the test),

4.2.2 The maximum dose rate to which the devices will be subjected during the test, and

4.2.3 The bias conditions to which the devices will be subjected during the test.

## 5. Significance and Use

5.1 The use of FXR or LINAC radiation sources for the determination of high dose-rate burnout in semiconductor devices is addressed in this guide. The goal of this guide is to provide a systematic approach to testing semiconductor devices for burnout or survivability.

5.2 The different types of failure modes that are possible are defined and discussed in this guide. Specifically, failure can be defined by a change in device parameters, or by a catastrophic failure of the device.

5.3 This guide can be used to determine if a device survives (that is, continues to operate and function within the specified performance parameters) when irradiated to a predetermined dose-rate level; or, the guide can be used to determine the dose-rate burnout failure level (that is, the minimum dose rate at which burnout failure occurs). However, since this latter test is destructive, the minimum dose-rate burnout failure level must be determined statistically.

## 6. Interferences

6.1 There are several interferences that need to be considered when this test procedure is applied.

6.2 *Ionizing Dose Damage*—Devices may be permanently damaged by the accumulation of ionizing dose. This limits the number of radiation pulses that can be applied during burnout testing. The ionizing dose sensitivity depends on fabrication

techniques and device technology. Metal-oxide, semiconductor (MOS) devices are especially sensitive to ionizing dose damage; however, bipolar devices with oxide-isolated sidewalls or bipolar linear circuits may also be affected by low levels of ionizing dose. The maximum ionizing total dose exposure of the devices under test must not exceed fifty percent (50 %) of their typical ionizing dose failure level for that specific part type to ensure that device failure is caused by the transient dose rate, and not by the total accumulated ionizing total dose.

6.2.1 *Radiation Level Step Size*—The size of the steps between successive radiation pulses (that is, the dose-rate increment) limits the accuracy of the determination of the burnout failure level.

6.3 *Latchup*—Some types of integrated circuits are susceptible to latchup during transient radiation exposure. If latchup occurs, the device will not function correctly until power is temporarily removed and reapplied. Permanent damage (burnout) may also occur during latchup; it is primarily caused by a substantial increase in power supply current that leads to increased power dissipation, localized heating, or both. Latchup is temperature dependent and testing at elevated temperature is required to establish worst-case operating conditions for latchup. Latchup testing is addressed elsewhere.

6.4 *Charge Build-up Damage*—Damage to a device may occur due to direct electron irradiation of the DUT leads. When using direct electron irradiations (see Section 7), all device leads must be shielded from the electron beam to reduce charge pickup that could cause abnormally large voltages to be generated on internal circuitry and produce damage not related to ionizing dose-rate burnout.

6.5 *Bias and Load Conditions*—Bias and load conditions may affect the survivability and burnout response. Usually, the objective of the test is to determine the dose-rate survivability or burnout under worst-case operating conditions.

6.5.1 *Input Bias*—Unless otherwise specified, the input bias condition shall be chosen to provide the worst-case operating conditions. For example, for digital devices, input pins that are in the high state should be tied directly to the supply voltage. For analog devices, input voltages generally should be at the maximum levels expected to be used. For both digital and analog devices, it is desirable to perform the burnout test using at least two different input conditions, such as minimum input levels and maximum input levels, or alternately with half the inputs tied high and the remaining tied low.

6.5.2 *Output Loading*—Unless otherwise specified, the DUT outputs shall be chosen to provide the worst-case conditions for device operation. For digital devices, worst case conditions should include maximum fan-out. For analog devices, worst-case conditions should include maximum output voltage or load current. For both digital and analog devices, it may be desirable to perform the burnout test using at least two different output conditions.

6.5.3 *Operating Voltage*—Unless otherwise specified, testing shall be performed using maximum operating voltages. The test setup shall be configured such that the transient power supply photocurrent shall not be limited by the external circuit resistance or lead inductance. Power supply stiffening capacitors shall be included to keep the power supply voltage from varying more than 10 % of the specified value during and after the radiation pulse.

6.6 *Over-Stress*—The high dose-rate burnout test should be considered destructive. ~~Peak photocurrents in excess of 2 to 3 amperes can occur during these tests. These large~~ Large currents can produce localized metallization or semiconductor melting that is not readily detected by electrical tests, ~~and both, but tests; both~~ may adversely affect device reliability. Devices that exceed the manufacturer's absolute limits for current or power during burnout tests should not be used in high-reliability applications.

6.7 *Test Temperatures*—Tests shall be performed at ambient temperature, or at a temperature agreed upon between the parties to the test. If tests are performed in a vacuum, overheating may become an issue, requiring control of the device's temperature.

## 7. Apparatus

7.1 *General*—The apparatus used for tests should include as a minimum, the radiation source, dosimetry equipment, a test circuit board, line drivers, cables and electrical instrumentation to measure the transient response, provide bias, and perform functional tests. Precautions shall be observed to obtain an electrical measurement system with ample shielding, satisfactory grounding, and low noise from electrical interference or from the radiation environment.

7.1.1 *Radiation Source*—The most appropriate radiation source for high dose-rate burnout tests is a FXR machine. The required dose rate for burnout cannot usually be achieved using an electron linear accelerator (LINAC) because LINACs typically cannot produce a sufficiently high dose rate over the critical active area of the device under test; however, some LINACs are capable of meeting these requirements. Linear accelerators shall be used only with agreement of all parties to the test.

7.1.2 *Flash X-ray (Photon Mode)*—The choice of facilities depends on the available dose rate as well as other factors including photon spectrum, pulse width and electron end-point energy. The selection of the pulse width is affected by; (a), the dose rate required, and (b), the ionizing dose accumulation per pulse. Finally, the FXR electron end-point energy must be greater than 1 MeV to ensure that the resulting bremsstrahlung photons have sufficient energy to penetrate the DUT.

7.1.3 *Flash X-ray (E-beam Mode)*—A FXR or LINAC operated in the e-beam mode generally provides a higher dose rate than similar machines operated in the photon mode. However, testing in the e-beam mode requires that appropriate precautions be taken and special test fixtures be used to ensure meaningful results. The beam produces a large magnetic field, which may interfere with the instrumentation, and can induce large circulating currents in device leads and metals. The beam also produces air ionization, induced charge on open leads, and unwanted cable currents and voltages. For FXRs, E-beam testing is generally performed with the DUT mounted in a vacuum to reduce air ionization effects. Special dosimetry techniques are required to ensure proper